

Search Notes

Application/Control No.

10/716,879

Examiner

ALEX LIEW

Applicant(s)/Patent under
Reexamination

SCHEIER ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/103,115-118,124-127,305,306 limited to text search	3/10/2008	AL
345/156-184 limited to text search	3/31/2008	AL